G-RAD Workshop - Grenoble Radiation Testing of semiconductor devices and systems

Thursday, 10 December 2020

Session 4 - Alternative Testing Methods (10:40 - 13:00)

-Conveners: Ruben Garcia Alia

time	[id] title	presenter
10:40	[39] Recent advances in pulsed X-ray single-event testing	LALUMONDIERE, Stephen
11:05	[8] Laser testing as an optimized complement of Heavy Ion for SEE testing - experiences from Airbus DS	WEULERSSE, Cécile
11:25	[29] Fast neutron GENESIS platform	BAYLAC, Maud
11:40	[30] Neutron Irradiation Capabilities at the PTB Ion Accelerator Facility PIAF	NOLTE, Ralf
11:55	[28] Pulsed Synchrotron focalised X-rays and XFEL	CAPRIA, Ennio
12:10	[32] Pulsed-Laser Testing for Single-Event Effects Investigations	SHARP, RIchard
12:25	[33] Q&A Session on the limits of current radiation testing offer and emerging needs	